

Search Notes

Application/Control No.

10/705,818

Examiner

Chuck Huynh

Applicant(s)/Patent under
Reexamination

NAKAYAMA ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
Updated	Search	1/7/2007	CH
455	411	1/7/2007	CH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Class/Subclass	1/7/2007	CH
Combined Text and Class/Subclass search	1/7/2007	CH
Look over old arts	1/7/2007	